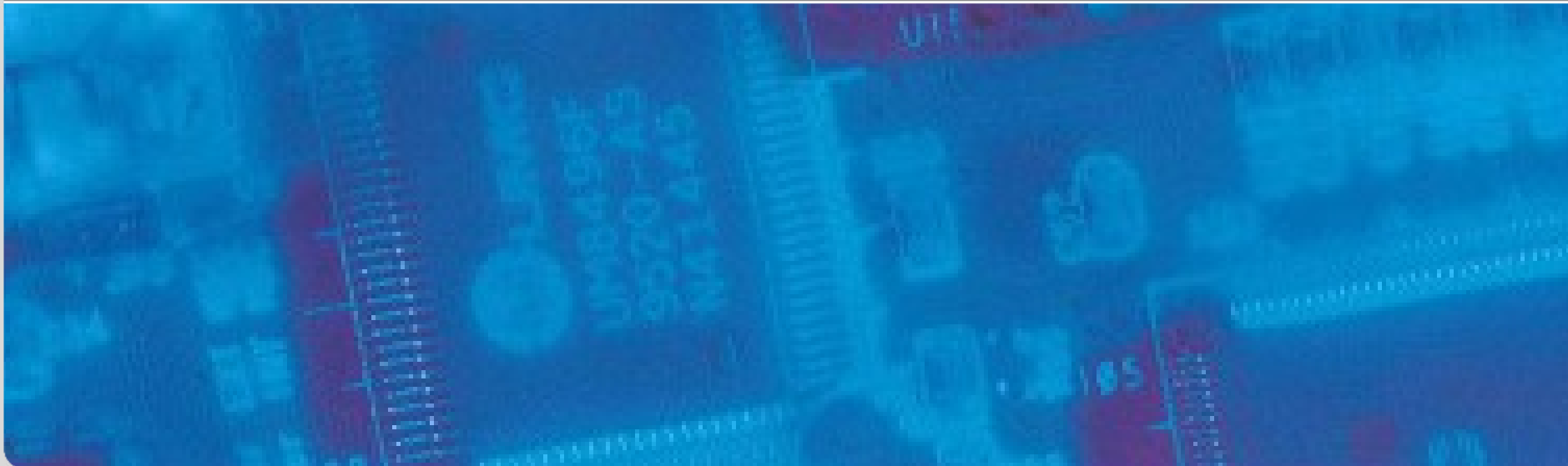


# Low Power Design

Hussam Amrouch, Volker Wenzel on behalf of Prof. Dr. Jörg Henkel  
Summer Term 2016

CES – Chair for Embedded Systems





# Overview Low Power Design Lecture

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- Introduction and Energy/Power Sources (1)
- Energy/Power Sources(2): Solar Energy Harvesting
- Battery Modeling – Part 1
- Battery Modeling – Part 2
- Hardware power optimization and estimation – Part 1
- Hardware power optimization and estimation – Part 2
- Hardware power optimization and estimation – Part 3
- Low Power Software and Compiler
- Thermal Management – Part 1
- Thermal Management – Part 2
- Aging Mechanisms in integrated circuits
- **Lab Meeting**

# Agenda

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- Introduction of Theoretical Background (Volker)
- Lab Demo (Hussam)

# Means for Temperature Analysis

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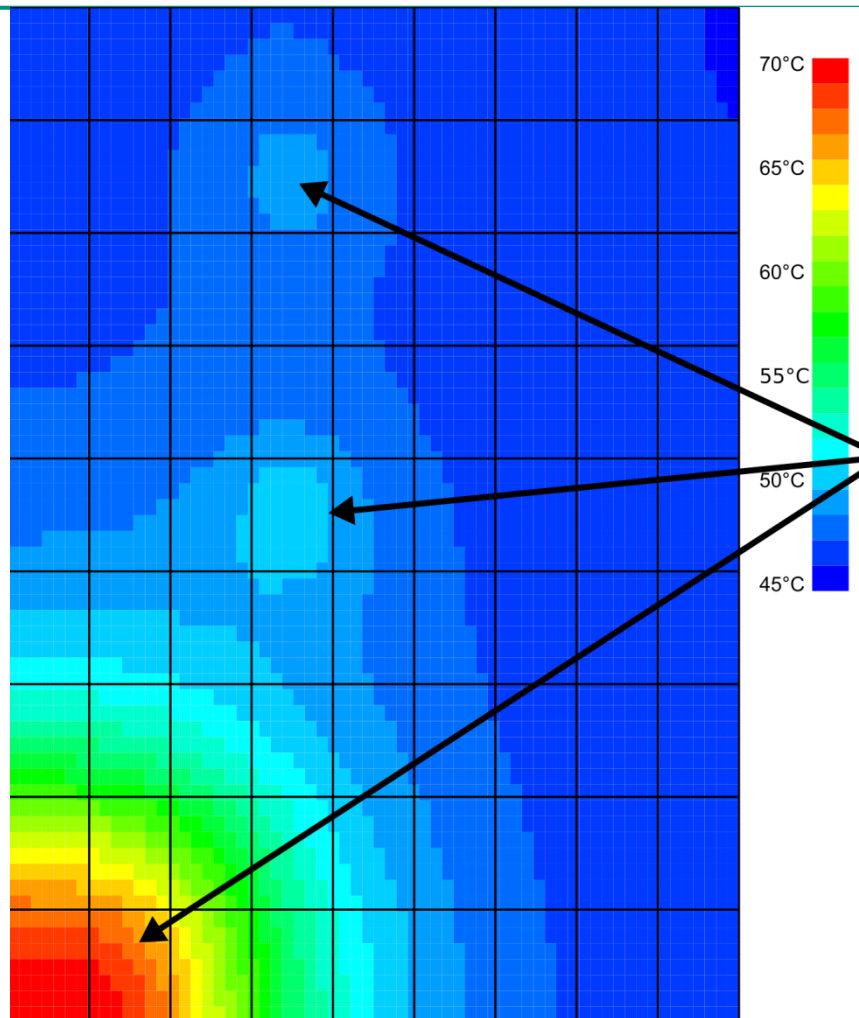
- Thermal Simulation
  - estimate thermal profile from power trace in different of blocks (e.g. using HotSpot)
- Thermal Sensor
  - hard sensor (e.g. thermal diode)
  - soft sensor (e.g. ring oscillator)
- Thermal Camera
  - very accurate reading
  - Thermal image shows actual temperature distribution across chip

# HotSpot vs. Measurement

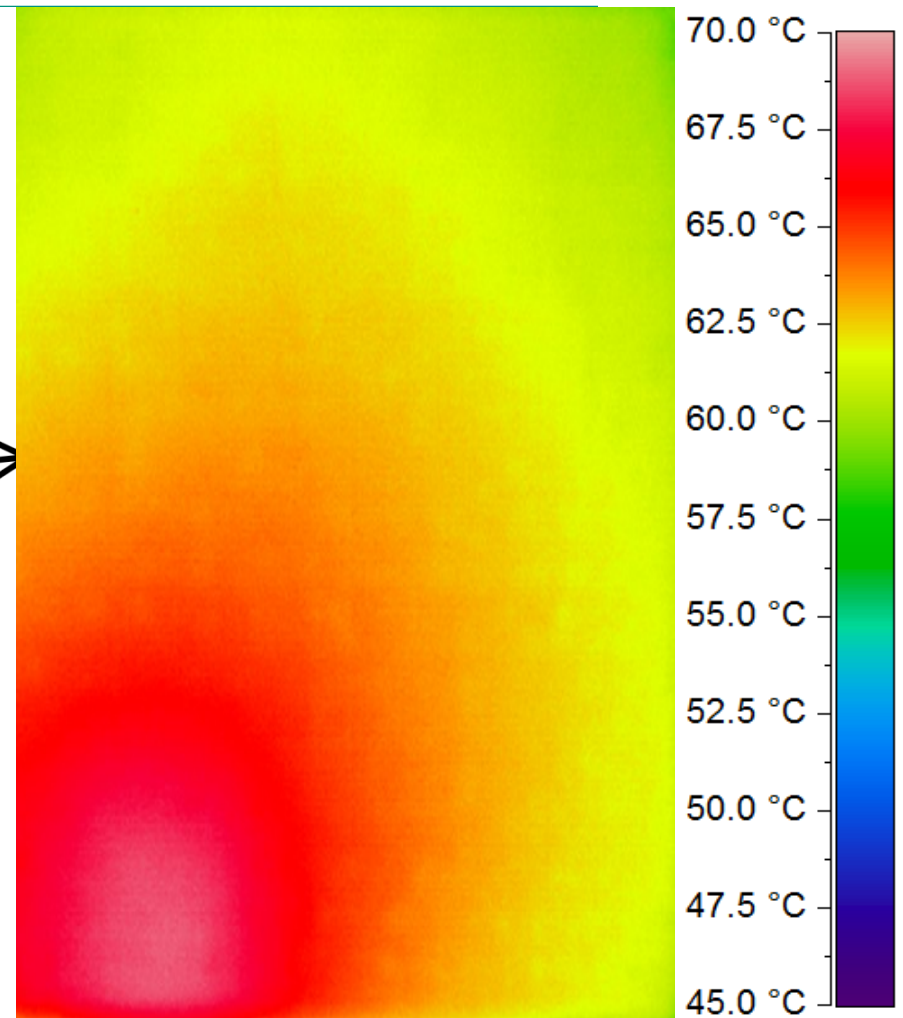
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- comparison of HotSpot and measurement w/ thermal camera (next slide)
- issues w/ on-chip sensors
  - calibration
  - chip area
  - gradients, inhomogeneous heat distribution; thermal diode might measure the wrong spot of the chip
- thermal camera superior way of measuring temperature

# HotSpot Simulation of FPGAs



simulated thermal image



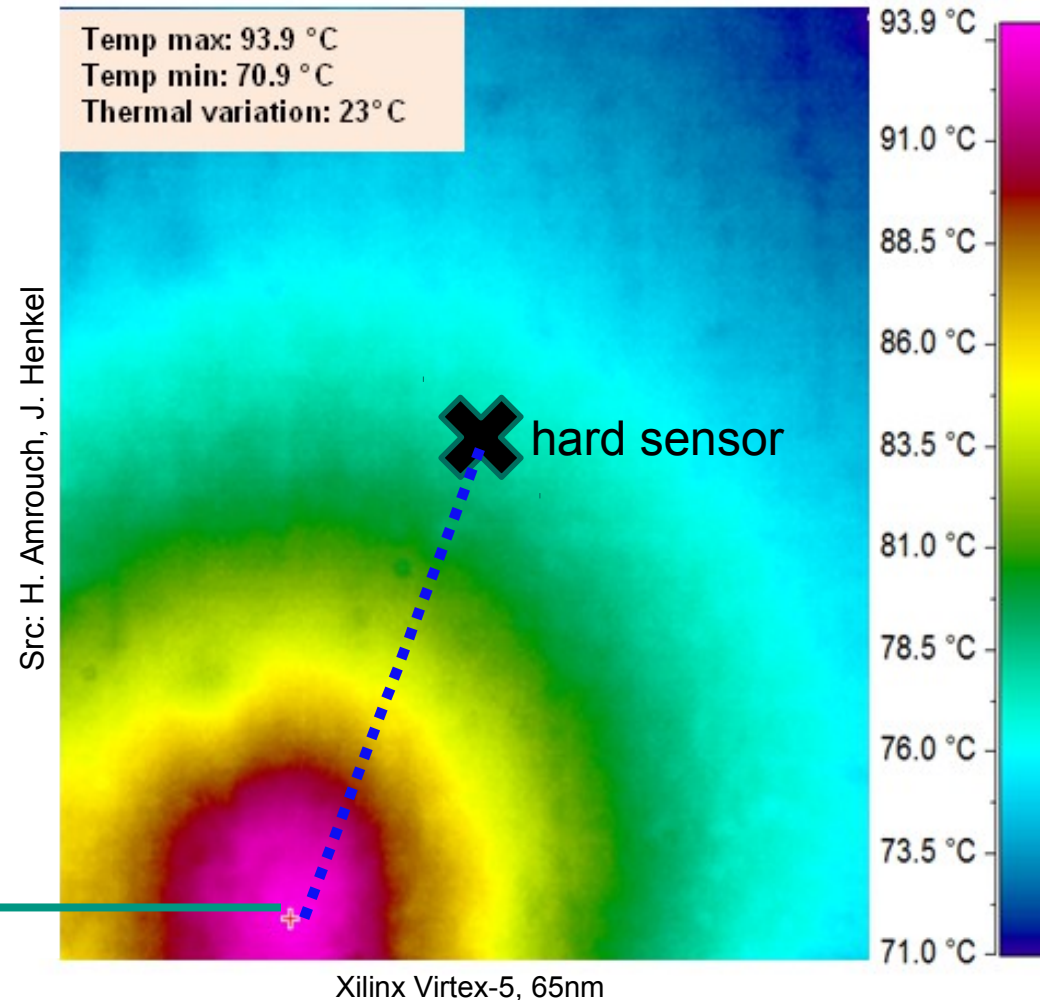
infrared image from the thermal camera

src: H. Amrouch et. al, "Analyzing the thermal hotspots in FPGA-based embedded systems," FPL, 2013.

# Hard Thermal Sensors

More than 10°C difference between the reading of sensor and the real peak temperature.

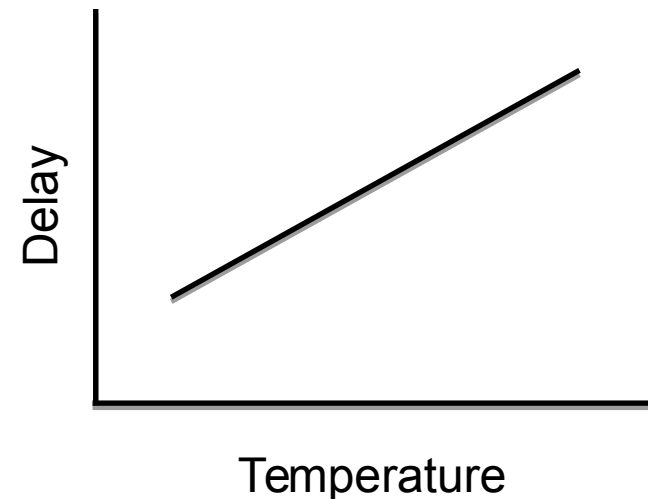
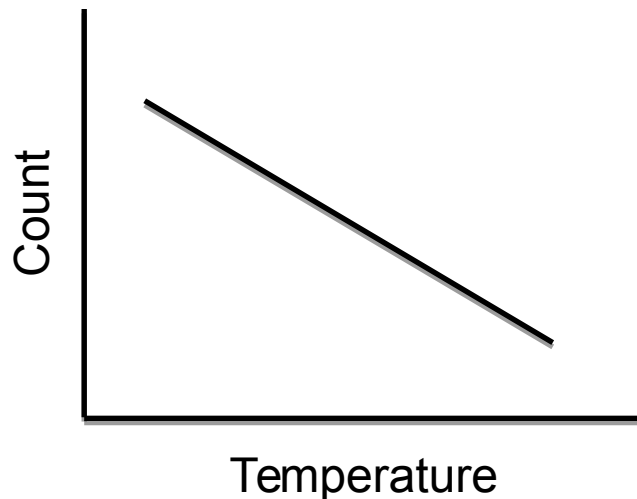
The potential hotspot reaches 94°C and is located at the corner of chip



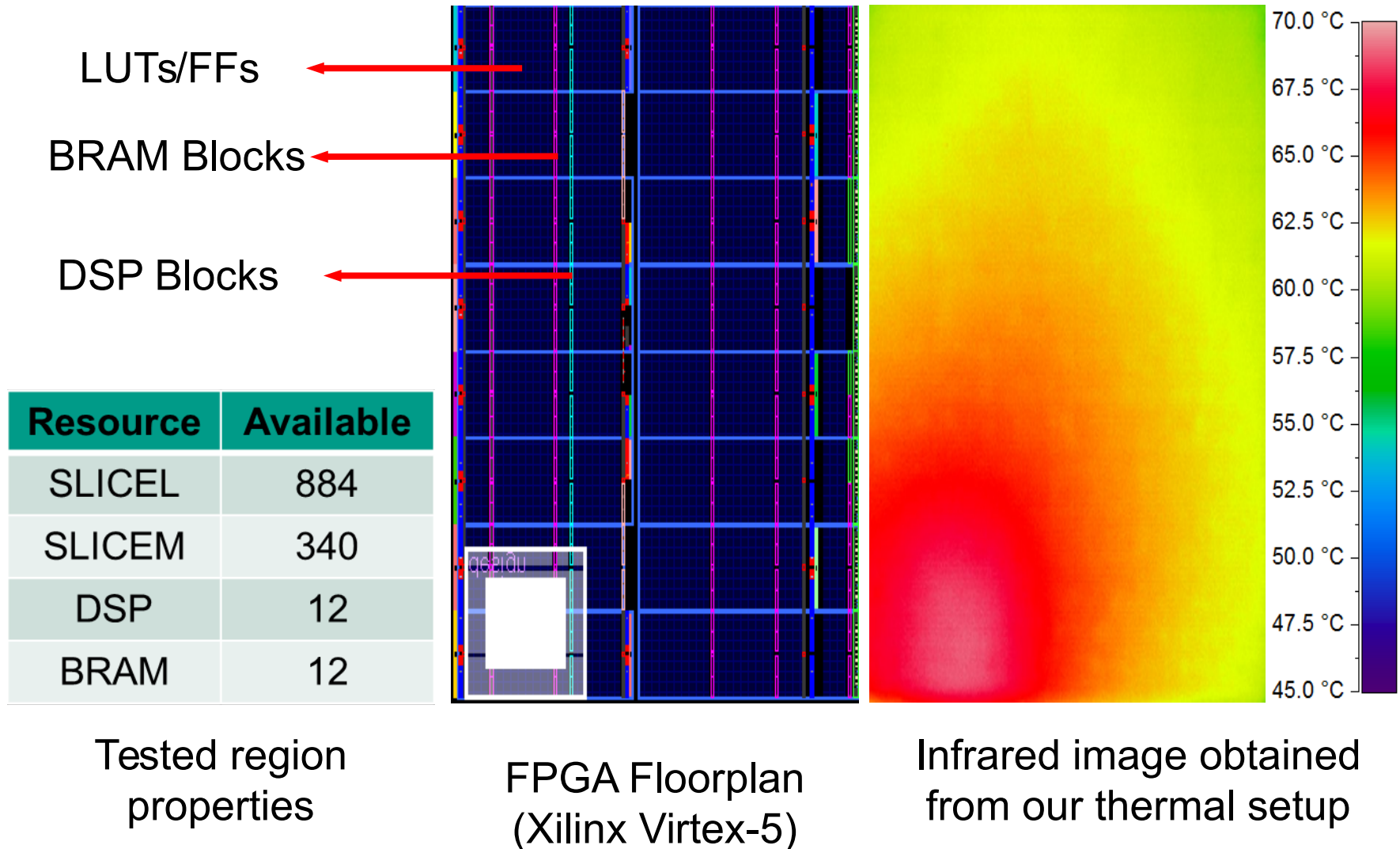


## ■ Soft sensors (e.g. ring oscillator):

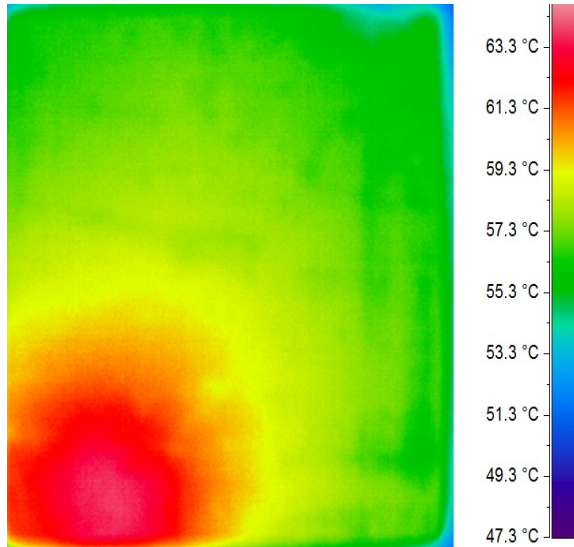
- + low power consumption
- + low area overhead
  - Many can be placed across the chip
- requires calibration (e.g. central hard sensor)



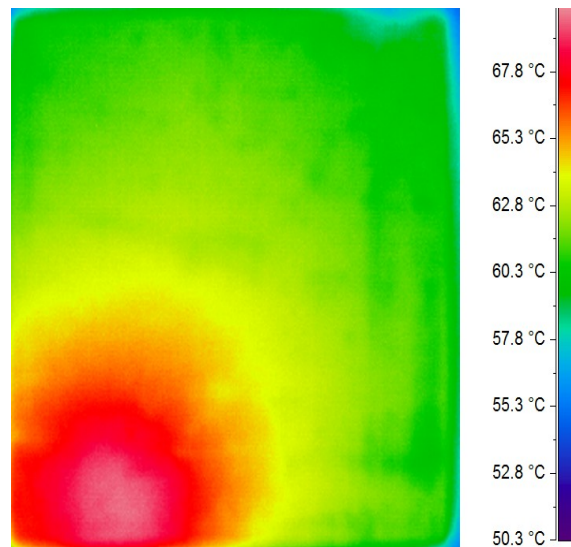
# Thermal behavior in FPGA



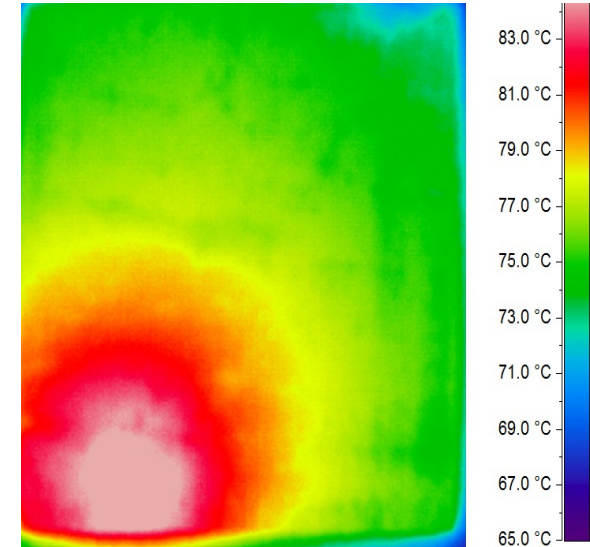
# Thermal Behavior for Different FPGA Resources



Design: Only-Slices  
Peak Temp = 64 °C  
Thermal variation = 13 °C



Design: Slices+BRAMs  
Peak Temp = 70 °C  
Thermal variation = 15 °C

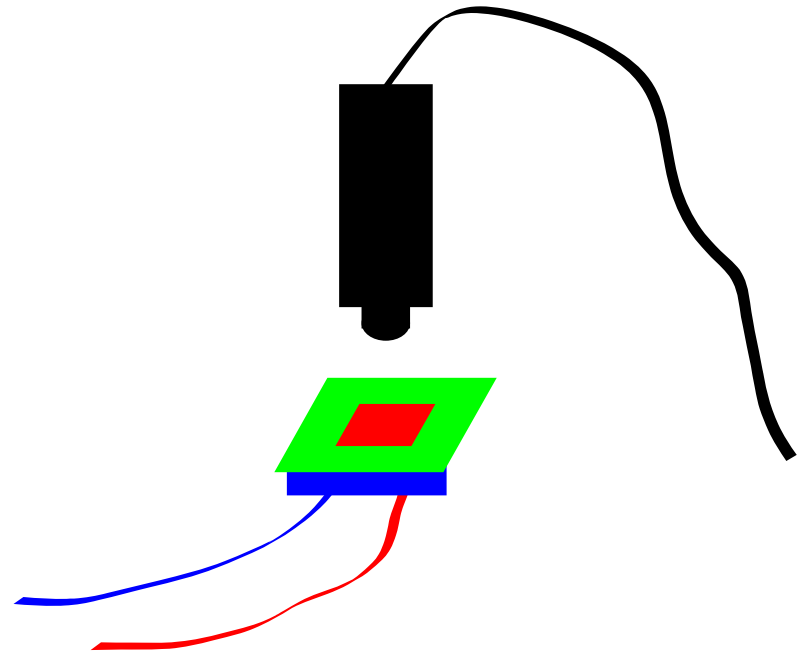


Design: Slices+BRAMs+DSPs  
Peak Temp = 86 °C  
Thermal variation = 19 °C

Slices = LUTs + FFs, ambient temp = 30 °C

Src: H. Amrouch, J. Henkel

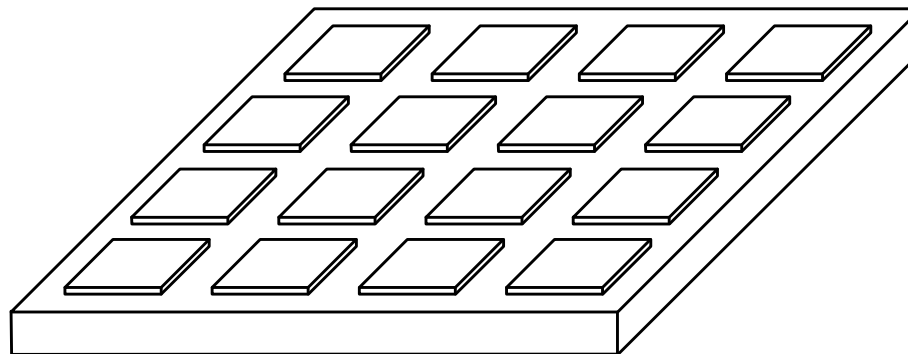
- need to remove packaging from chip
- alternative approach: IR-oil



# Which chips are suitable for the thermal setup?

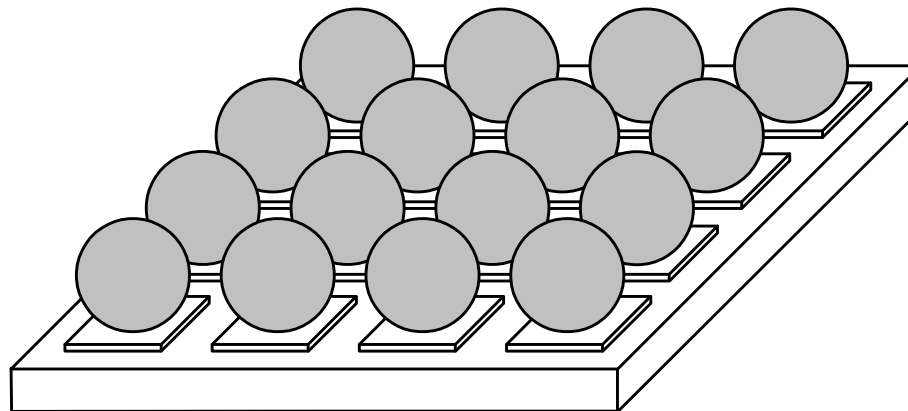
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- *controlled collapse chip connection* (C4) aka **Flip Chips**
- bare silicon must be visible with packaging removed

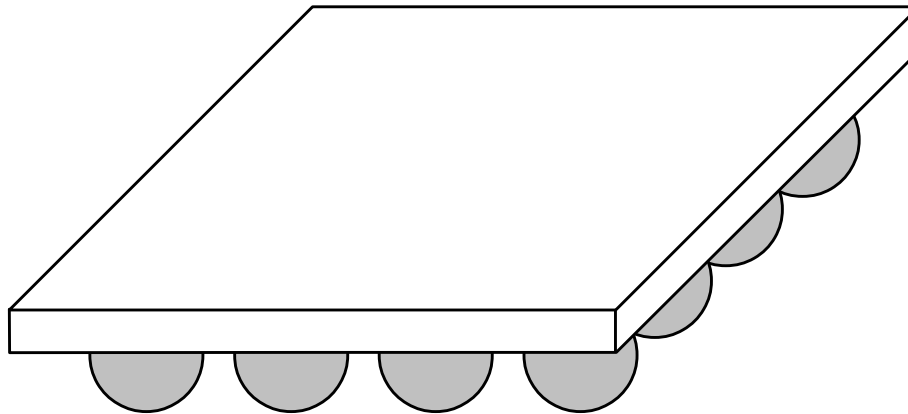


Integrated circuits are created on the wafer

[src:en.wikipedia.org/wiki/Flip\\_chip](https://en.wikipedia.org/wiki/Flip_chip)

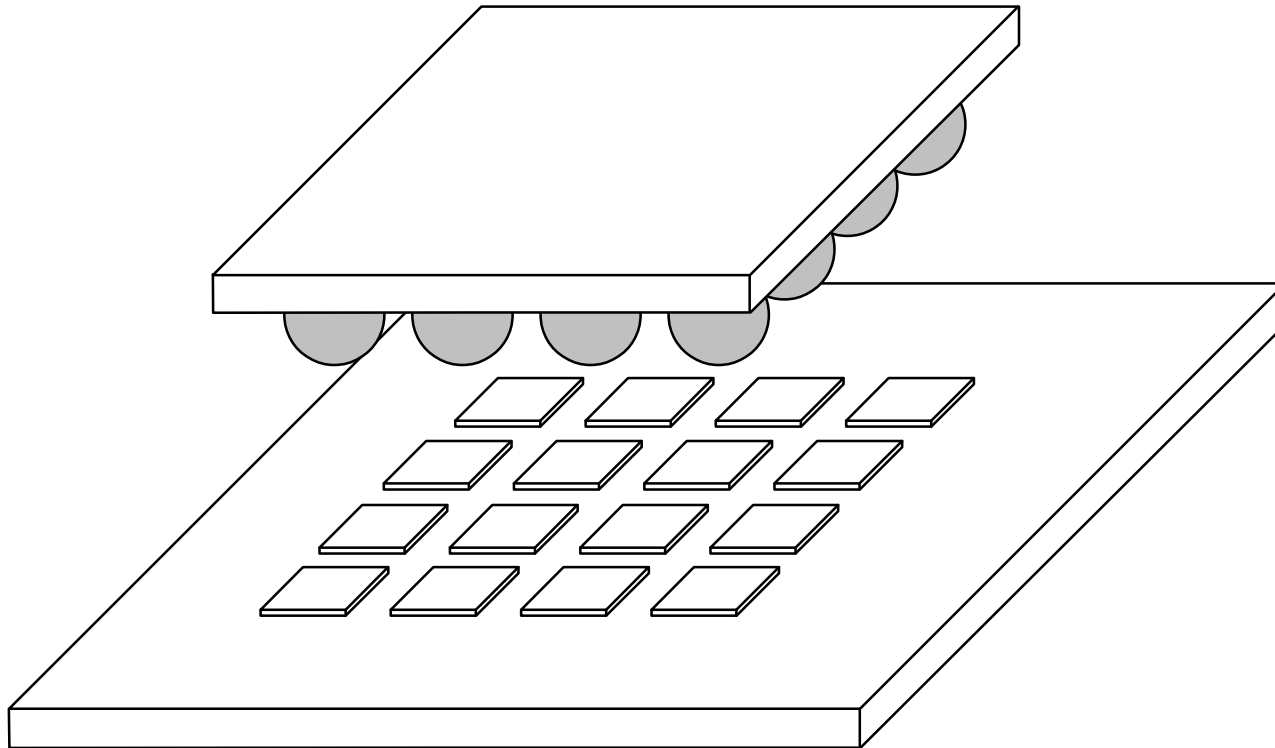


[src:en.wikipedia.org/wiki/Flip\\_chip](http://src.en.wikipedia.org/wiki/Flip_chip)



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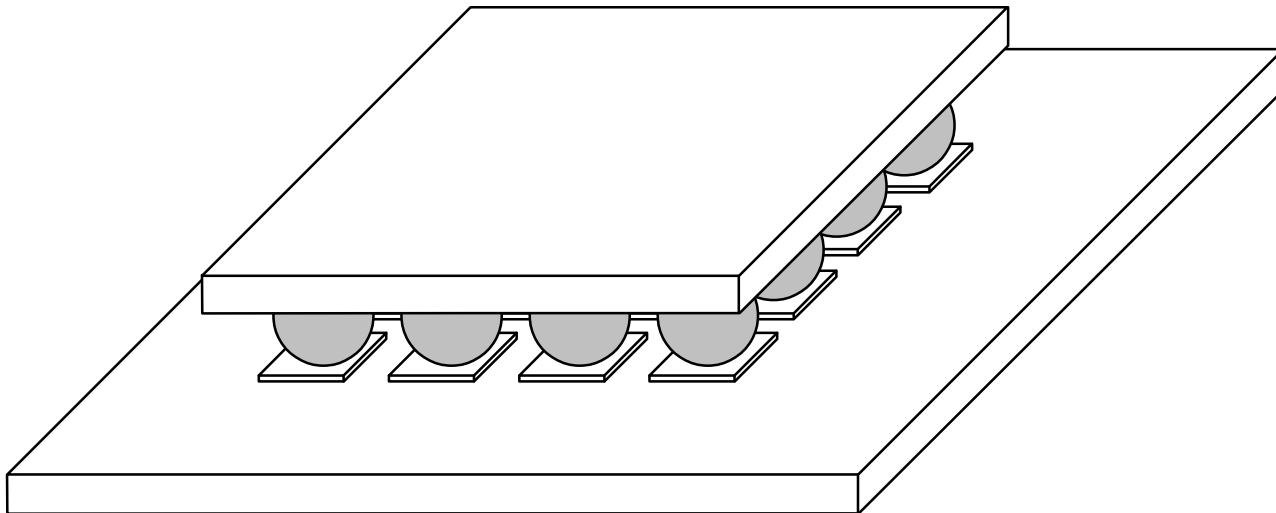




[src:en.wikipedia.org/wiki/Flip\\_chip](http://src.en.wikipedia.org/wiki/Flip_chip)

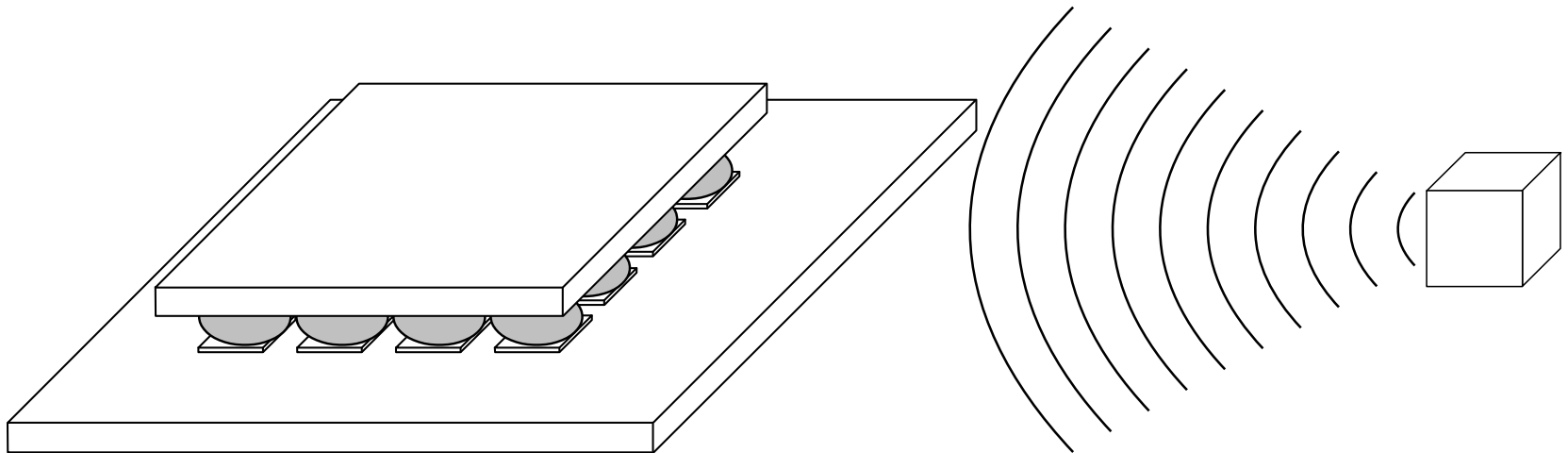
# Fabrication of Flip Chips

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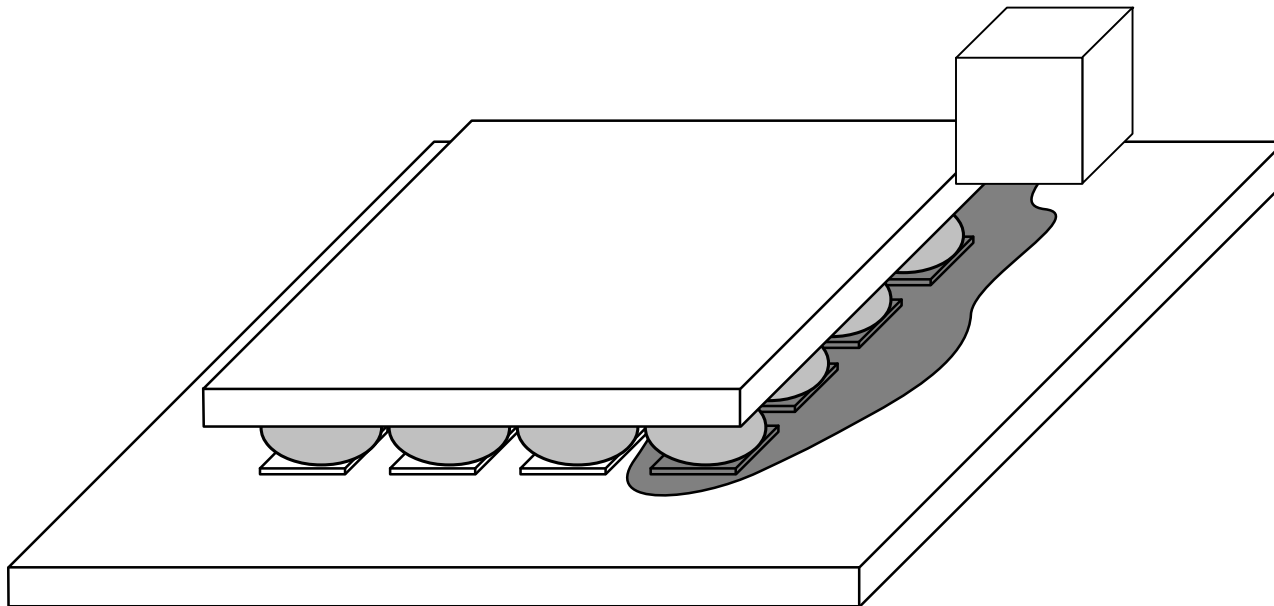


[src:en.wikipedia.org/wiki/Flip\\_chip](http://src.en.wikipedia.org/wiki/Flip_chip)

# Fabrication of Flip Chips



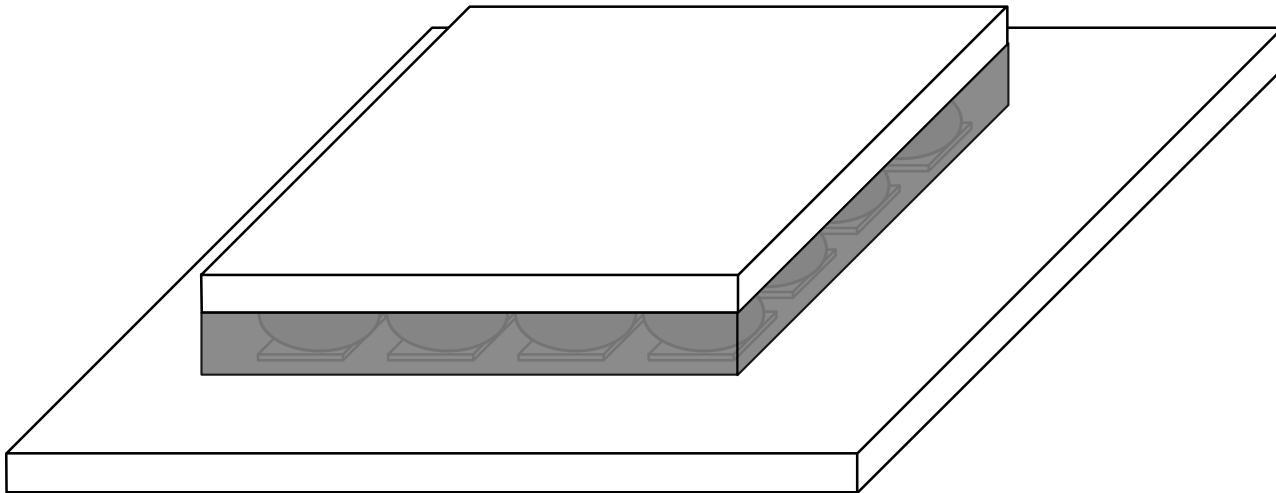
[src:en.wikipedia.org/wiki/Flip\\_chip](http://src.en.wikipedia.org/wiki/Flip_chip)



[src:en.wikipedia.org/wiki/Flip\\_chip](http://src.en.wikipedia.org/wiki/Flip_chip)

# Fabrication of Flip Chips

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[src:en.wikipedia.org/wiki/Flip\\_chip](http://src.en.wikipedia.org/wiki/Flip_chip)

# Thermal Camera

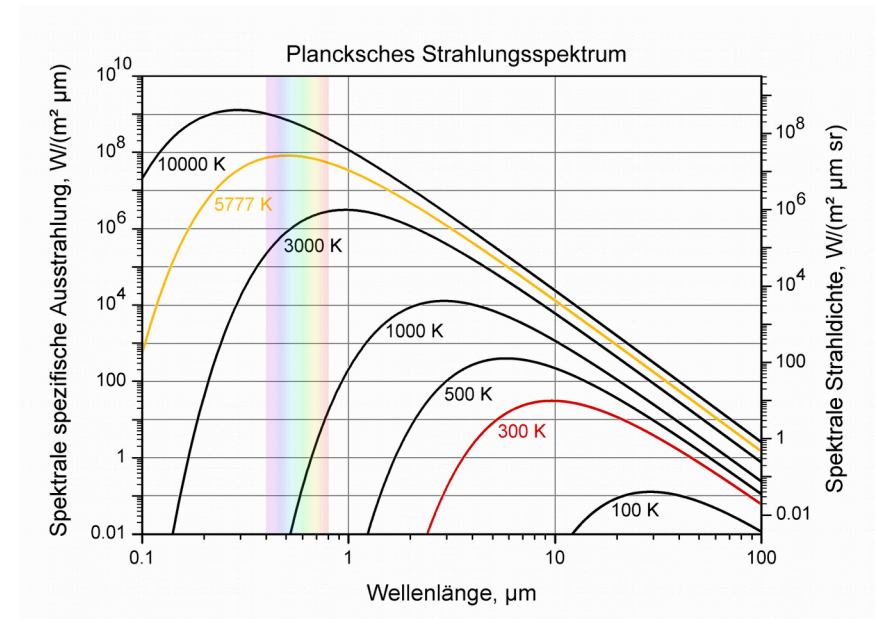
- infrared camera
- $8\mu\text{m}$ - $14\mu\text{m}$
- precise, contact-less temperature measurement



DIAS PyroView 380L compact  
src: DIAS

- hot bodies radiate!
- spectrum is characteristic of equilibrium temperature
- infrared for usual temperatures

$$P = \sigma A T^4$$

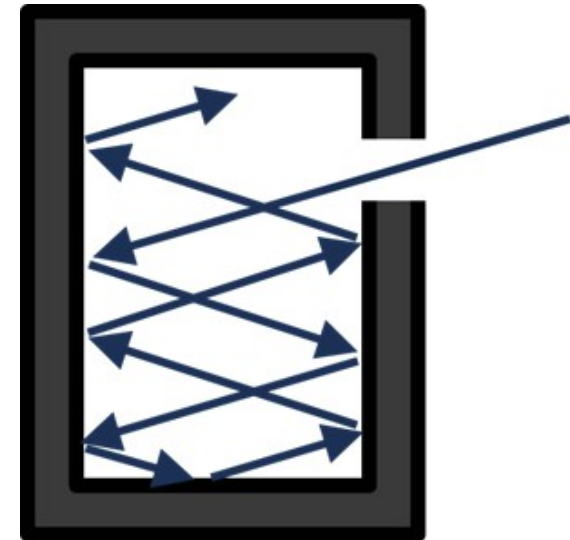


$$B_\lambda(T) = \frac{2hc^2}{\lambda^5} \frac{1}{e^{\frac{hc}{\lambda k_B T}} - 1}$$

[src:en.wikipedia.org](http://src:en.wikipedia.org)

# Black Bodies

- idealized physical body
  - absorbs all incident radiation
  - is in thermal equilibrium
  - optimal diffuse emitter
- 
- real bodies: **emissivity  $\varepsilon$**
  - = energy emitted / energy emitted by black body  
at the same temperature
  - $\varepsilon$  between 0 and 1

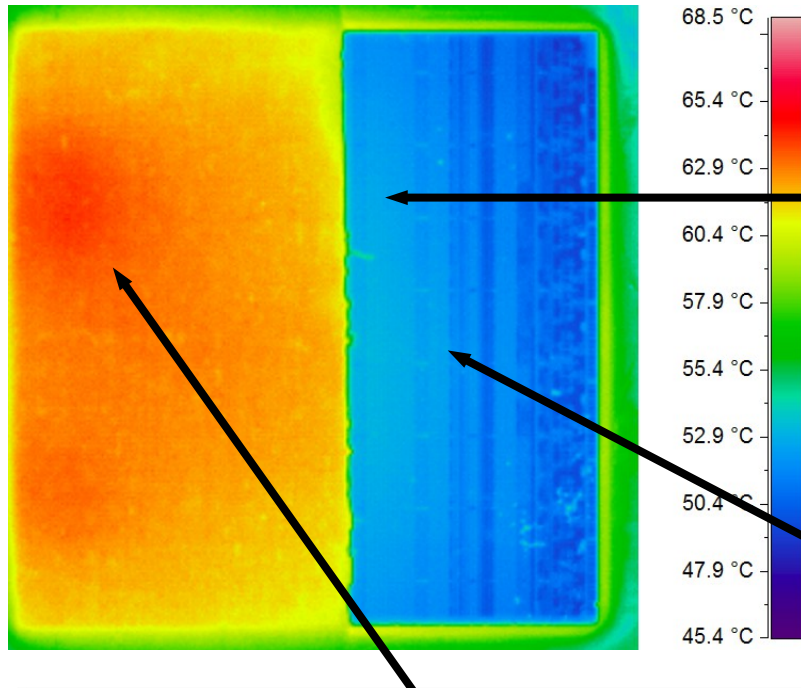


[src:en.wikipedia.org/wiki/Black\\_body](https://en.wikipedia.org/wiki/Black_body)



# Emissivity Problem

Src: H. Amrouch, J. Henkel



Surface of silicon wafer with a low emissivity ( $\sim 0.7$ ) leads to inaccurate measurements. Reflection from surroundings seriously impacts the measured heat.

Structure of BRAM blocks appear more clearly without the masking tape

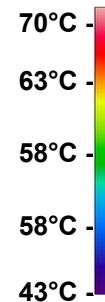
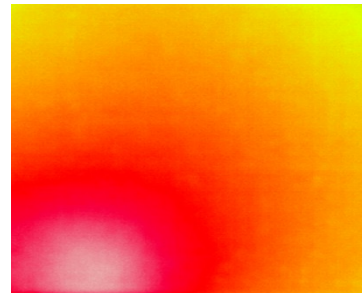
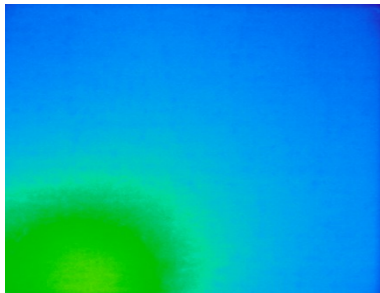
Masking tape with an emissivity of 0.9 coating the left half of chip shows that the temperature here is more closer to the actual one.

The variation in temperature between the right and left half is around 20°C

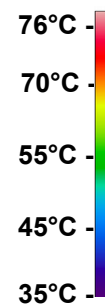
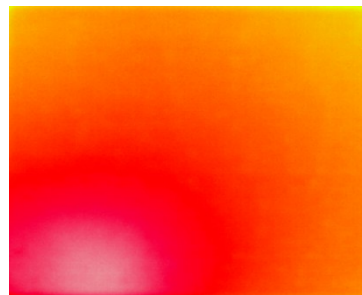
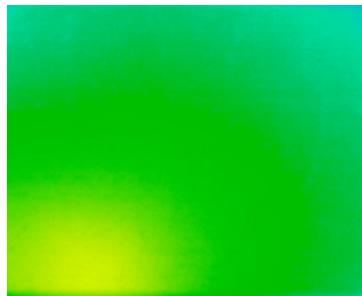
# Impact of ambient temperature

Ambient  
Temperature: 20°C

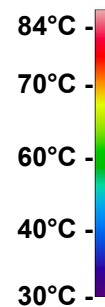
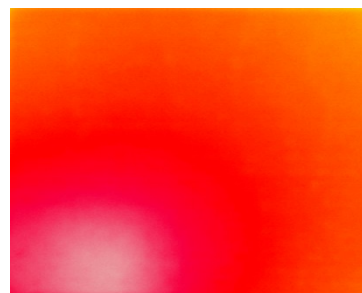
Ambient  
Temperature: 30°C



Design: FFs/LUTs



Design: FFs/LUTs +  
BRAM blocks



Design: FFs/LUTs +  
BRAM blocks + DSPs

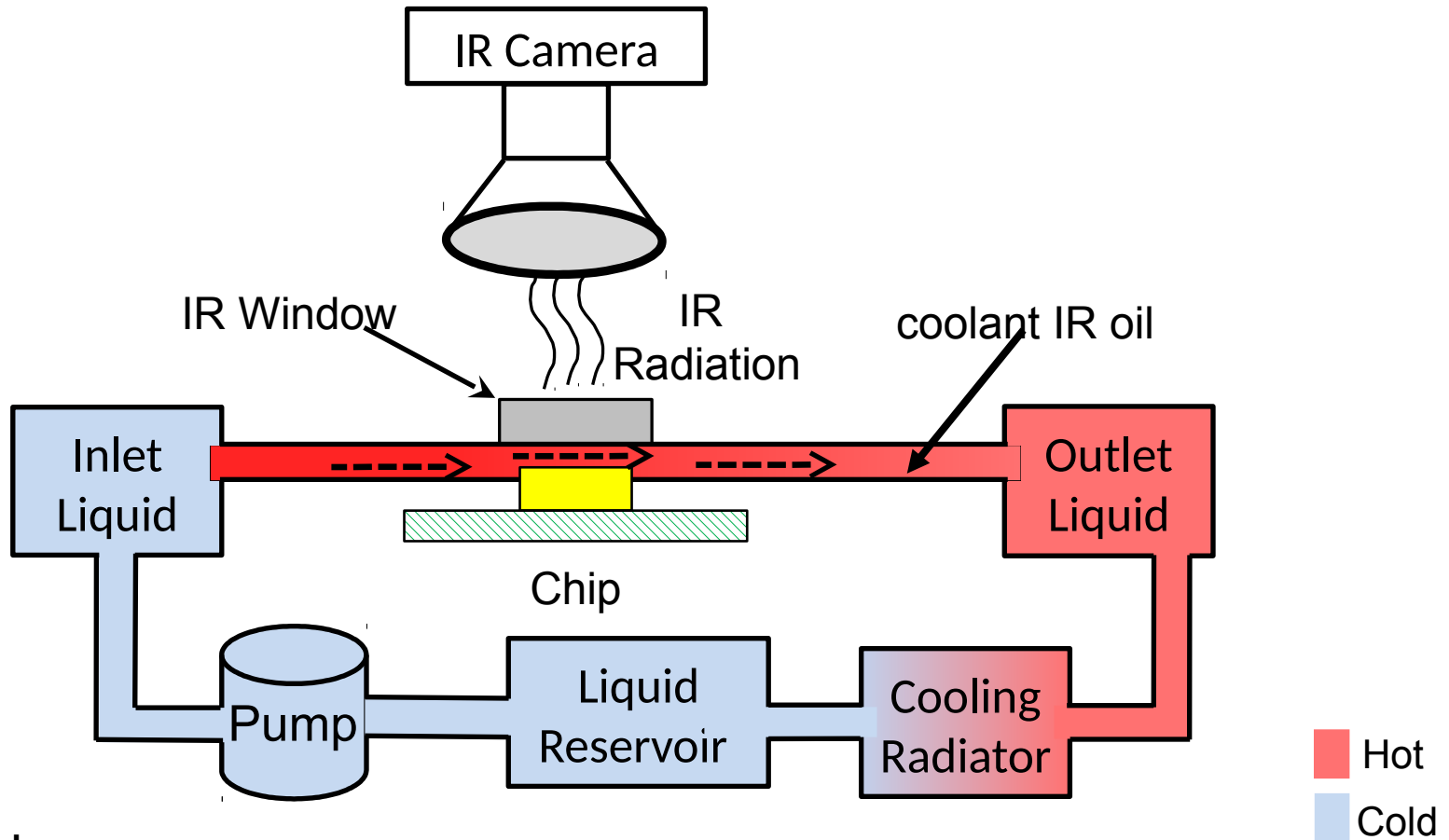
src: H. Amrouch, J. Henkel

# IR Thermography of Processors

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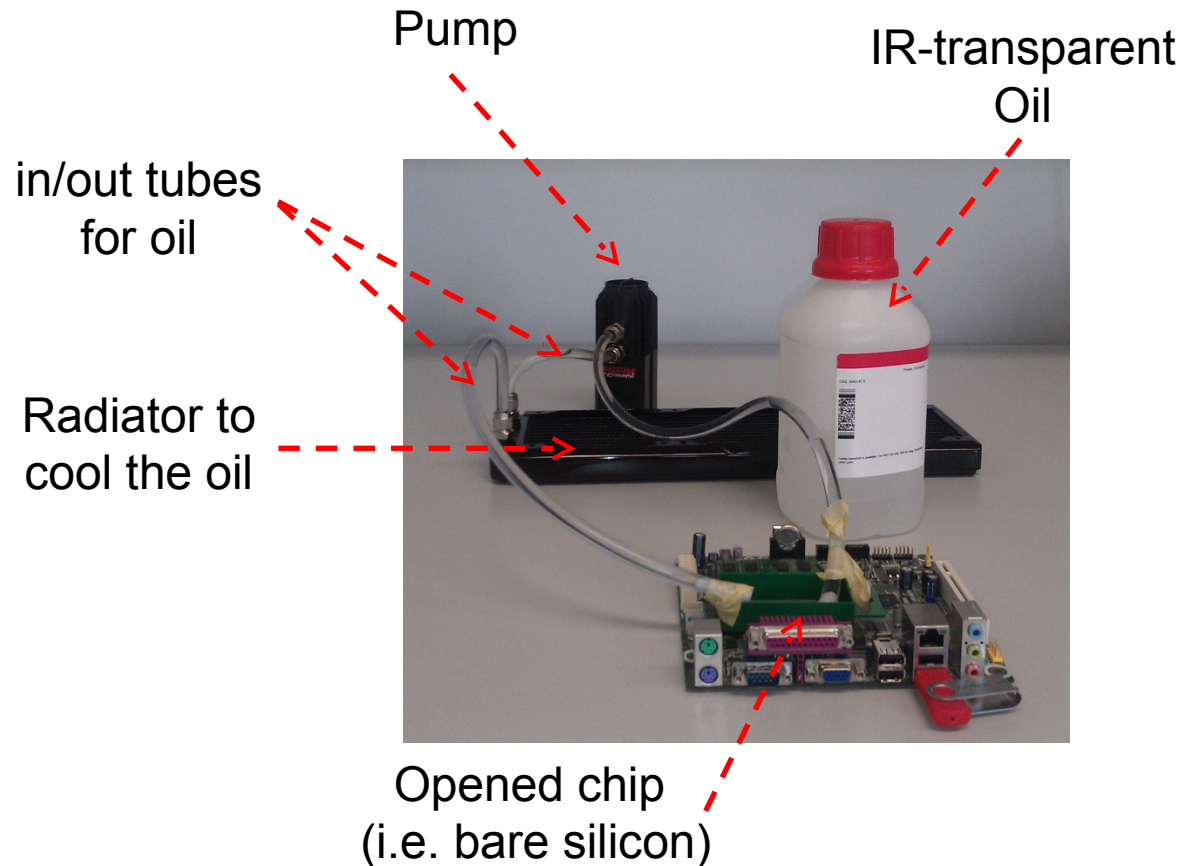
- Major Challenge: Constructing **IR-transparent cooling** that
  - allows the IR radiation emitted from the chip to reach the thermal camera.
  - prevents the chip from burning up.

# IR Thermography: State-of-the-Art



Src: H. Amrouch

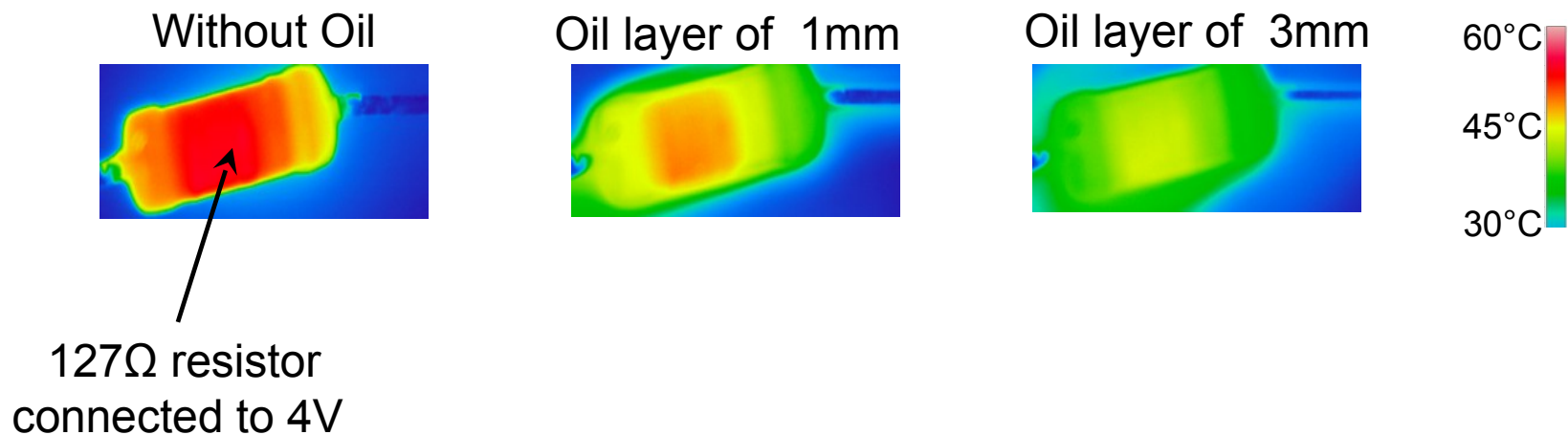
# IR Thermography: State-of-the-Art



## Liquid-based Cooling Technique

Src: H. Amrouch

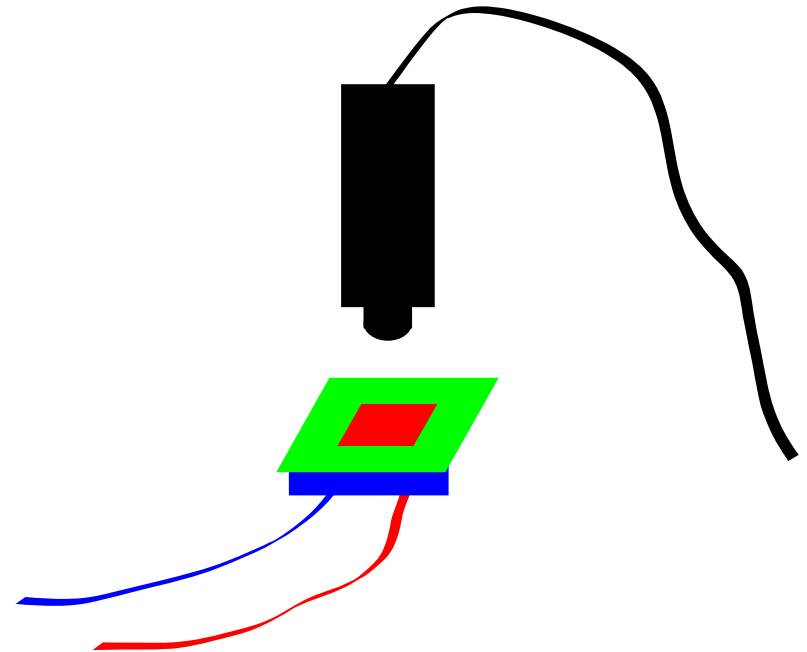
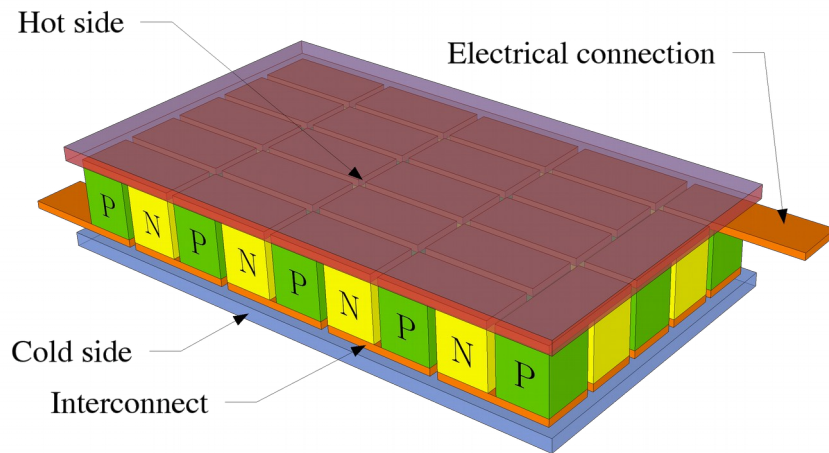
# Impact of Oil



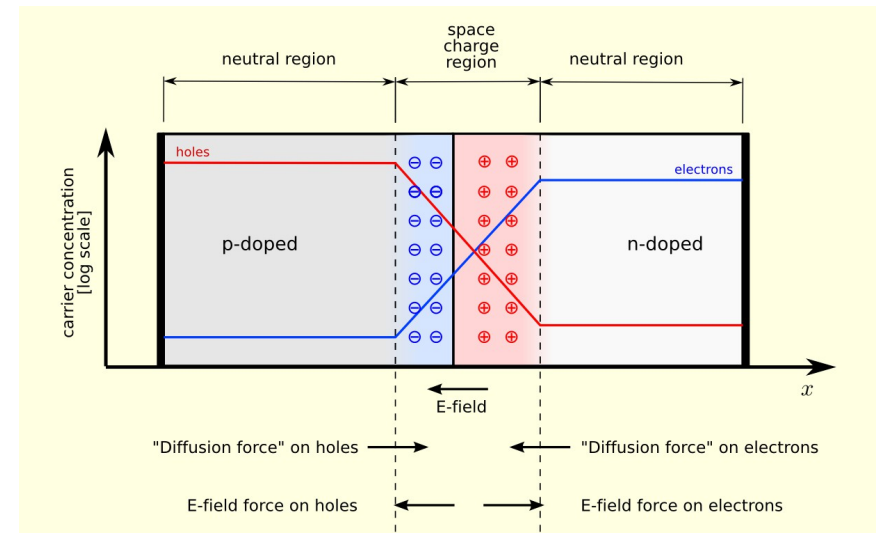
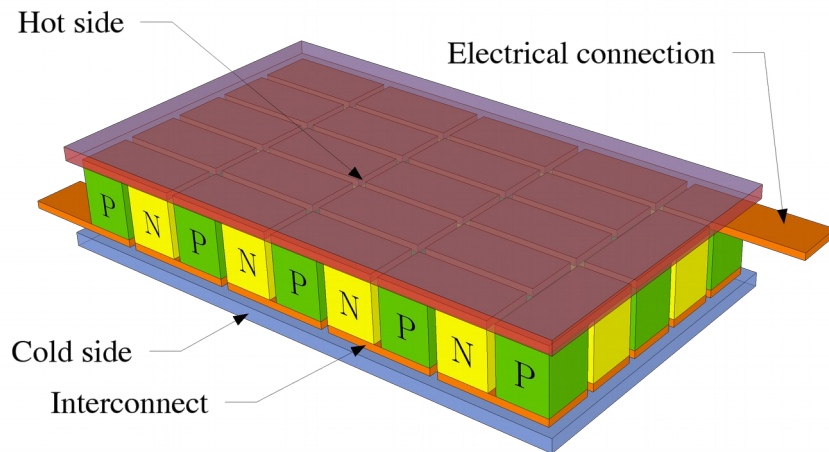
**Thermal convection destroys the clarity of the captured IR images**

Src: H. Amrouch

# Thermoelectric Cooling



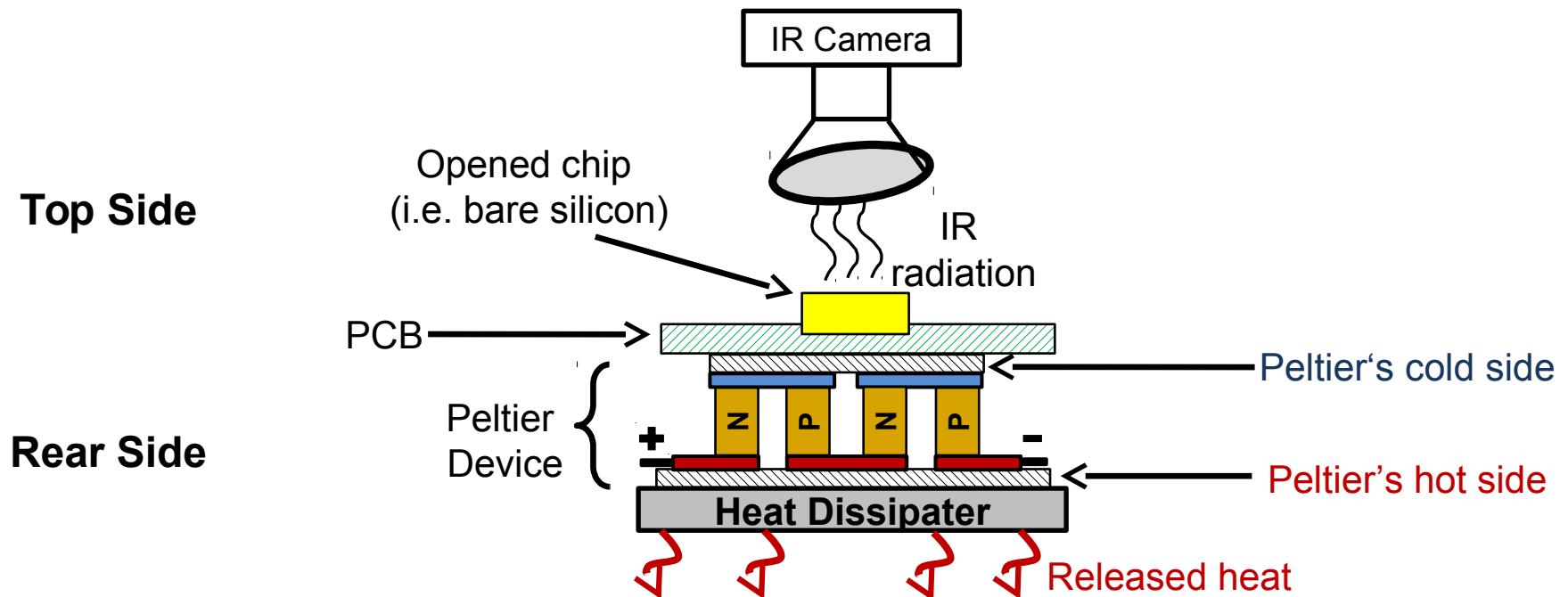
# Thermoelectric Cooling





# IR Thermography: Built Thermal Setup

- It continuously **cools** the measured chip from its **rear side**.
- **Thermoelectric** technology has been employed
  - ▢ It provides a stable/controlled source of cooling (**Peltier**).



src: H. Amrouch

# Opportunities for Bachelor/Master Theses



[ces.itec.kit.edu/69.php](http://ces.itec.kit.edu/69.php)